

Notice of References Cited

Application/Control No.

10/000,119

Applicant(s)/Patent Under
Reexamination
MALZBENDER ET AL.

Examiner

Phu K. Nguyen

Art Unit

2671

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
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FOREIGN PATENT DOCUMENTS

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	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	NEYRET et al., Pattern-Based Texturing Revisited, ACM, SIGGRAPH 99, 8/1999, pp. 235-242.
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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